



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki, et al. Art Unit : 2811
Serial No. : 10/727,651 Examiner : Unknown
Filed : December 5, 2003
Title : THIN FILM TRANSISTORS AND SEMICONDUCTOR DEVICE

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT AND SUBMISSION
OF CORRECTED FORM PTO-1449**

Supplemental to an information disclosure statement filed with the application on December 5, 2003, Applicants submit the attached corrected Form PTO-1449. All of the documents listed on the form PTO-1449 were cited in information disclosure statement filed with the application. The corrected Form PTO-1449 is being submitted to correct typographical errors in the description of three references identified as Desig. ID "AD," "BF" and "BN." Please note that the Patentee in Desig. ID "AD" has been changed from "Change, et al." to "Chang, et al." and the Publication Date in Desig ID as been changed from "04/1991" to "10/28/1992." In addition, the translation identification for TW310478 (Desig. ID "BF") has been changed from "Full" to "Abstract."

This statement is being filed before the receipt of a first Office action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: April 29, 2004



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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-051002	Application No. New Application
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Shunpei Yamazaki, et al.	
		Filing Date December 5, 2003	Group Art Unit Unknown
(37 CFR §1.98(b))			

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,766,477	08/23/1988	Nakagawa, et al.			
	AB	5,643,826	07/01/1997	Ohtani, et al.			
	AC	5,923,962	07/13/1999	Ohtani, et al.			
	AD	5,943,560	08/24/1999	Chang, et al.			
	AE	5,977,560	11/02/1999	Banerjee, et al.			
	AF	6,087,679	07/2000	Yamazaki, et al.			
	AG	US 2002/0043662	04/18/2002	Yamazaki, et al.			
	AH	US 2002/0038889	04/04/2002	Yamazaki, et al.			
	AI	US 2002/0014625	02/07/2002	Asami, et al.			
	AJ	US 2002/0008286	01/24/2002	Yamazaki, et al.			
	AK	US 2002/0040981	04/2002	Yamazaki, et al.			
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	AM	5,162,933	11/10/1992	Kakuda, et al.			
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	AS	6,107,654	08/22/2000	Yamazaki, et al.			
	AT	6,180,957	01/30/2001	Miyasaka, et al.			
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	AV	6,307,214	10/23/2001	Ohtani, et al.			
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	AX	6,335,541	01/01/2002	Ohtani, et al.			
	AY	6,348,368	02/19/2002	Yamazaki, et al.			
	AZ	6,452,211	09/17/2002	Ohtani, et al.			

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 12732-051002	Application No. New Application
	Applicant Shunpei Yamazaki, et al.			
	Filing Date December 5, 2003		Group Art Unit Unknown	

	BA	6,495,886	12/17/2002	Yamazaki, et al.			06/13/2002
	BB						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	BC	8-78329	03/22/1996	Japan			Abstract	
	BD	7-130652	05/19/1995	Japan			Abstract	
	BE	TW 251379	07/11/1995	Taiwan			Full	
	BF	TW 310478	07/11/1997	Taiwan			Abstract	
	BG	JP 11-345767	12/1999	Japan			Abstract	
	BH	JP 4-349619	12/1992	Japan			Abstract	
	BI	EP 984317	03/2000	Europe			In English	
	BJ	02-219234	08/31/1990	Japan			Abstract	
	BK	11-204434	07/30/1999	Japan			Abstract	
	BL	11-284198	10/15/1999	Japan			Abstract	
	BM	11-307783	11/05/1999	Japan			Abstract	
	BN	EP 510969	10/28/1992	Europe			In English	
	BO							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
X	BP	R. Ishihara et al.; "Micro Texture Analysis Of Location Controlled Large Si Grain Formed by Exciter-Laser Crystallization Method"; <i>AMLCD '99 Digest of Technical Papers 1999 Tokyo, Japan</i> ; pp. 99-102; 1999
X	BQ	Seok-Woon Lee et al.; "Low Temperature Poly-Si Thin-Film Transistor Fabrication by Metal-Induced Lateral Crystallization"; <i>IEEE Electron Device Letters, Vol. 17, No. 4</i> , pp. 160-162; April 1996
	BR	

X Did not receive

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	